

#### **Product Features**

- 1805~1880MHz
- 69.2W Saturated Power @ 48V
- 14% Drain Efficiency @ 33dBm
- Internally 50ohm Matched
- 2-Stage Amplifier Module
- GaN on SiC Technology

#### **Applications**

- Massive MIMO
- 4G System
- Multi-Band, Multi-Mode
- Multi-Carrier
- RRH Drive Amplifier





Package Type: PP-3G

### **Description**

The SDM18005-30H is a fully integrated micro-strip GaN Hybrid power amplifier module designed for applications in 4G LTE MIMO systems, small cells and low power remote radio heads. SDM Series is an integrated 2-stage power amplifier module, 50ohm input and output impedance matched device can deliver up to 69.2W of saturation power and operating drain voltage 48V. This device is size 8x14x2.6mm and is packaged in a ceramic surface mount package.

### **Typical Performance**

 $(V_{DS} = +48V, T_{C} = 25^{\circ}C, 50\Omega)$ 

Fraguency [MH	-1	Peak Power	Average Power*1				
Frequency [MHz		Power [W]	Power [W]	Gain [dB]	Drain Efficiency [%]	ACLR [dBc]	
1815		68.2	2.0	42.2	14.7	-44.1	
1842.5		69.8	2.0	42.1	14.6	-44.0	
1870		68.9	2.0	42.0	14.6	-44.1	

#### Note

#### **Absolute Maximum Ratings**

Rating	Symbol	Value	Unit	Condition
Drain to Source Voltage	V <sub>DSS</sub>	100	V	Tc=25 °C
Gate to Source Voltage	$V_{GS}$	-10, +2	V	Tc=25 ℃
Operating Voltage	$V_{DD}$	52	$V_{DC}$	
Storage Temperature	$T_{STG}$	-40, +125	°C	
<b>Case Operating Temperature</b>	$T_{\rm C}$	-30, +125	°C	
Operating Junction Temperature*1	$T_{\mathrm{J}}$	225	°C	
Soldering Temperature*2	$T_{S}$	250	°C	

#### Note

<sup>\*1</sup> Measured in the SDM18005-30H test board amplifier circuit, under LTE 20MHz 1carrier, PAR 7.5dB @0.01% probability on CCDF.

<sup>\*1</sup> Continuous use at maximum temperature will affect MTTF.

 $<sup>*2\</sup> Refer to the\ Application\ Note (AN-002)\ on\ soldering\ -\ "Solder\ Condition\ for\ RFHIC's\ GaN\ Device"$ 



# **Electrical Characteristics**\*1 (T<sub>C</sub>=25°C unless otherwise noted)

	~	~		_				
Characteristics	Conditions	Symbol	Min	Тур	Max	Unit		
DC Characteristics (Main)								
Maximum Forward Gate Current	Tc= 25℃	$I_{GMAX}$	-	-	12	mA		
Maximum Drain Current*2	Tc= 25℃	$I_{DMAX}$	-	-	4.50	A		
Power Dissipation	Tc= 85 ℃	$P_{DMAX}$	-	-	51.9	W		
Gate Threshold Voltage	$V_{DS} = 10V$ $I_{D} = 10.8mA$	V <sub>GS(TH)</sub>	-3.8	-3.0	-2.3	$V_{DC}$		
Gate Quiescent Voltage	$V_{DS} = 48V$ $I_{D} = 100mA$	$V_{GS(Q)}$	-3.7	-2.9	-2.2	V <sub>DC</sub>		
Drain-Source Breakdown Voltage	$V_{GS} = -8V$ $I_{D} = 10.8mA$	V <sub>BR</sub>	150	-	-	V		
Saturated Drain Current*3	$V_{DS} = 6V$ $V_{GS} = 2V$	$I_{DS}$	9.0	10.8	-	A		
Gate Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	I <sub>GLKG150</sub>	-3.3	-	-	mA		
Drain Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	I <sub>DLKG150</sub>	-	-	4.3	mA		
	DC C	Characteristics (1	Drive)					
Maximum Forward Gate Current	Tc= 25℃	$I_{GMAX}$	-	-	1	mA		
Maximum Drain Current*2	Tc= 25℃	$I_{DMAX}$	-	-	0.6	A		
Power Dissipation	Tc= 85 ℃	$P_{DMAX}$	-	_	16.5	W		
Gate Threshold Voltage	$V_{DS} = 10V$ $I_{D} = 1.04mA$	V <sub>GS(TH)</sub>	-3.8	-3.0	-2.3	$V_{DC}$		
Gate Quiescent Voltage	$V_{DS} = 48V$ $I_{D} = 20mA$	$V_{GS(Q)}$	-3.7	-2.9	-2.2	V <sub>DC</sub>		
Drain-Source Breakdown Voltage	$V_{GS} = -8V$ $I_{D} = 1.04\text{mA}$	- V <sub>BR</sub>	150	-	-	V		
Saturated Drain Current*3	$V_{DS} = 6V$ $V_{GS} = 2V$	$I_{ m DS}$	0.8	1.0	-	A		
Gate Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	$I_{ m GLKG150}$	-0.3	-	-	mA		
Drain Leakage Current	$V_{GS} = -8V$ $V_{DS} = 150V$	I <sub>DLKG150</sub>	-	-	0.4	mA		

#### Note

<sup>\*1</sup> Measured on wafer prior to packaging.

<sup>\*2</sup> Current Limit for long term, reliable operation

<sup>\*3</sup> Scaled from PCM data.



Characteristics Conditions		Symbol	Min	Тур	Max	Unit	
RF Characteristics (F=1842.5MHz unless otherwise noted)							
Saturated Output Power*1,4	$V_{DS} = 48V$	P <sub>SAT</sub>	56	69.2	100	W	
Modulated Gain*2	$V_{DS} = 48V$	$G_{P}$	38	42	45	dB	
Wodulated Gain	$P_{OUT} = 33dBm$	o <sub>p</sub>				u.b	
Linearity*2	$V_{DS} = 48V$	ACLR	-55	-44	-30	dBc	
Linearity	$P_{OUT} = 33dBm$						
Madulated Duein Eccion av*2	$V_{DS} = 48V$		12	14	20	%	
Modulated Drain Efficiency*2	$P_{OUT} = 33dBm$	η				70	
Output Mismatch Stress <sup>*1, 3</sup>	$\begin{aligned} \mathbf{V}_{DS} &= \mathbf{48V} \\ \mathbf{P}_{OUT} &= \mathbf{P}_{SAT} \ \mathbf{Pulsed} \end{aligned}$	VSWR	-	-	10:1	Ψ	

#### Note

<sup>\*1</sup> Pulse width  $10\mu sec$ , Pulse period  $100\mu sec$ .

<sup>\*2</sup> Measured in the SDM18005-30H test board amplifier circuit, under LTE 20MHz 1carrier, PAR 7.5dB @0.01% probability on CCDF. Drive Idq=20mA, Main Idq=100mA

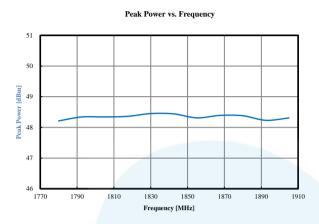
<sup>\*3</sup> Measured in the SDM18005-30H test board amplifier circuit. No damage at all phase angles.

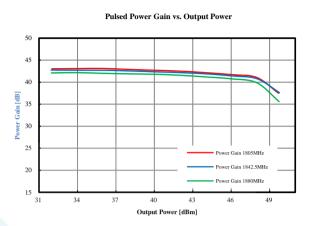
<sup>\*4</sup> Psat is defined as ΔPout/ΔPin<0.1, where ΔPin is increased input power, ΔPout is increased output power.



#### **Typical Pulsed Signal Performance**

(Tc=25°C, Measured in the SDM18005-30H test board amplifier circuit)

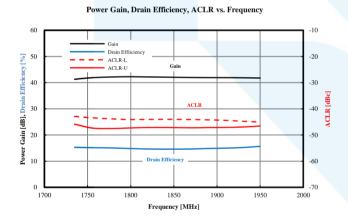




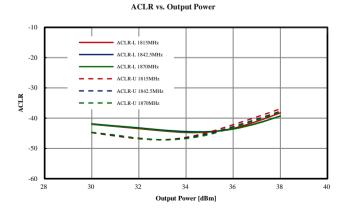
 $V_{DS}$  = 48V, Drive Idq=20mA, Main Idq=100mA Pulse width 100 $\mu$ sec, Pulse period 1ms

## **Typical Modulated Signal Performance**

(Tc=25°C, Measured in the SDM18005-30H test board amplifier circuit)





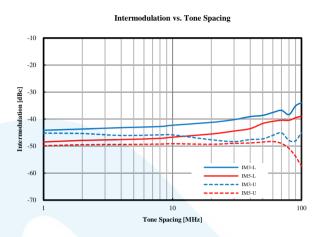


 $V_{DS} = 48V, \quad Drive\ Idq = 20mA, \quad Main\ Idq = 100mA$  LTE 20MHz 1carrier, PAR 7.5dB @0.01% probability on CCDF.



#### **Typical 2-tone Intermodulation Imbalance Performance**

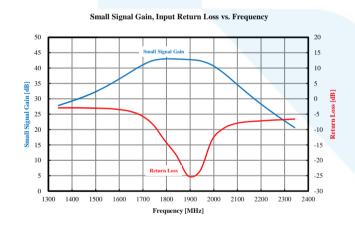
(Tc=25°C, Measured in the SDM18005-30H test board amplifier circuit)

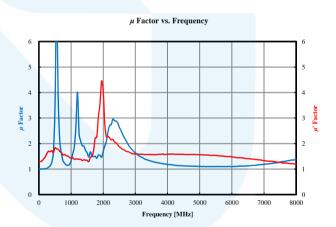


2-tone Power = 33dBm,  $V_{DS} = 48V$ , Drive Idq=20mA, Main Idq=100mA

#### **Typical Small Signal Performance**

(Tc=25°C, Measured in the SDM18005-30H test board amplifier circuit)

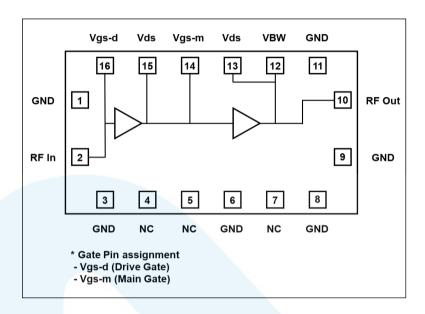




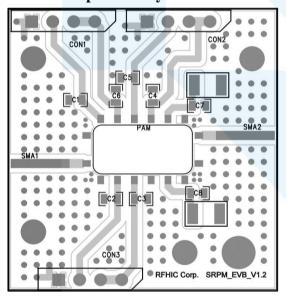
Input Power= -20dBm,  $V_{DS}$  = 48V, Drive Idq=20mA, Main Idq=100mA

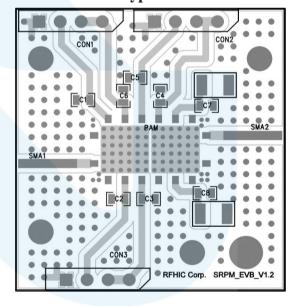


## **Block Diagram**



## Test Board Component Layout with Coin Embedded and Thermal Via Type



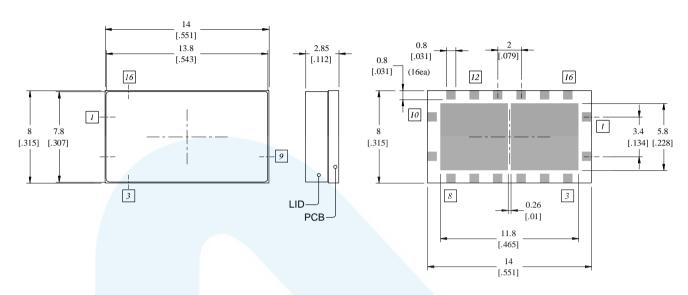


Part	Description	Part Number	Manufacturer
C4, C6, C7	1.0uF / 100V	GRM21BC72A105KE01	MURATA
C1, C5	4.7uF / 16V	TAJA475M016RNJ	AVX
PCB	2Layer, 20mil, 1oz	RO4350B	ROGERS
CON1~2	2.54mm Male Connector	5267-04A	MOLEX
SMA1~2	Female Connector	-	-
PAM	GaN Hybrid PAM	SDM18005-30H	RFHIC



## **Package Dimensions** (Type:PP-3G)

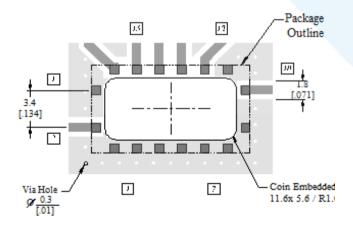
\* Unit: mm[inch] | Tolerance: ±0.15[.006]



Pin Description								
2	4	5	10	13	14	15	16	12
RF In	-	-	RF Out	$V_{\mathrm{DS}}$	$V_{GS-m}$	$V_{DS}$	$V_{GS-d}$	VBW
-	-	-	-	Main	Main	Drive	Drive	

<sup>\*</sup> Other Pins are GND.

## **Recommended Footprint & Coin Embedded**





#### **Revision History**

Part Number	Release Date	Version	Description	Data Sheet Status
SDM18005-30H	May. 2024	0.1	Initial version	Preliminary





#### Certification

This product is manufactured by a company that is certified for the AS9100D quality management system.

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